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U.S. Department of Commerce Patent and Trademark Office

Attomey's Docket No. 14603-012US1

Application No. 10/526,097

Information Disclosure Statement by Applicant
(Use several sheets if necessary)

Applicant Thomas Mueller

Filing Date September 7, 2005 Group Art Unit 2858

(37 CFR §1.98(b))

			U.S. Paten	t Documents			
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC	•					
	AD						
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	AG						
	АН						
	AI						
	AJ						
	AK						

	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Transla Yes	tion : No.
/AD/	AL .	07-022477	01/24/1995	Japan			Abstract	
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner Initial	Desig. ID	Document			
	_AQ	Perry R. J. "Analysis and Characterization of the Spectral Response of CMOS based Integrated Circuit (IC) Photodetectors" Proceedings of the Thirteenth Biennial University/Government/Industry			
		Microelectronics Symposium; pp 170-175			
	AR				
	AS	·			
	AT				

no date

Examiner Signature	/Anjan Deb/ (06/20/2007)	Date Considered
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Substitute Form PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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/AD/	AL	09045744	02/14/97	Japan (Abstract only)				
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V	AT	29 04 984	05/13/82	Germany			Abstract	

Other Documents (include Author, Title, Date, and Place of Publication)						
Examiner Initial	Desig. ID	Document				
	AU					

Examiner Signature /Anjan Deb/ (06/20/2007)	Date Considered
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